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晶体生长手册

晶体生长及缺陷形成概论

【第1册】

Springer
Handbook *of*
Crystal
Growth

〔美〕Govindhan Dhanaraj 等主编

(影印版)



哈尔滨工业大学出版社
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by Govindhan Dhanaraj, Kullaiah Byrappa, Vishwanath Prasad
and Michael Dudley

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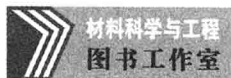
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Govindhan Dhanaraj, Kullaiah Byrappa,
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Springer Handbook of Crystal Growth

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序 言

多年以来，有很多探索研究已经成功地描述了晶体生长的生长工艺和科学，有许多文章、专著、会议文集和手册对这一领域的前沿成果做了综合评述。这些出版物反映了人们对体材料晶体和薄膜晶体的兴趣日益增长，这是由于它们的电子、光学、机械、微结构以及不同的科学和技术应用引起的。实际上，大部分半导体和光器件的现代成果，如果没有基本的、二元的、三元的及其他不同特性和大尺寸的化合物晶体的发展则是不可能的。这些文章致力于生长机制的基本理解、缺陷形成、生长工艺和生长系统的设计，因此数量是庞大的。

本手册针对目前备受关注的体材料晶体和薄膜晶体的生长技术水平进行阐述。我们的目的是使读者了解经常使用的生长工艺、材料生产和缺陷产生的基本知识。为完成这一任务，我们精选了50多位顶尖科学家、学者和工程师，他们的合作者来自于22个不同国家。这些作者根据他们的专业所长，编写了关于晶体生长和缺陷形成共计52章内容：从熔体、溶液到气相体材料生长；外延生长；生长工艺和缺陷的模型；缺陷特性的技术以及一些现代的特别课题。

本手册分为七部分。Part A介绍基础理论：生长和表征技术综述，表面成核工艺，溶液生长晶体的形态，生长过程中成核的层错，缺陷形成的形态。

Part B介绍体材料晶体的熔体生长，一种生长大尺寸晶体的关键方法。这一部分阐述了直拉单晶工艺、泡生法、布里兹曼法、浮区熔融等工艺，以及这些方法的最新进展，例如应用磁场的晶体生长、生长轴的取向、增加底基和形状控制。本部分涉及材料从硅和Ⅲ-V族化合物到氧化物和氟化物的广泛内容。

第三部分，本书的Part C关注了溶液生长法。在前两章里讨论了水热生长法的不同方面，随后的三章介绍了非线性和激光晶体、KTP和KDP。通过在地球上和微重力环境下生长的比较给出了重力对溶液生长法的影响的知识。

Part D的主题是气相生长。这一部分提供了碳化硅、氮化镓、氮化铝和有机半导体的气相生长的内容。随后的Part E是关于外延生长和薄膜的，主要包括从液相的化学气相淀积到脉冲激光和脉冲电子淀积。

Part F介绍了生长工艺和缺陷形成的模型。这些章节验证了工艺参数和产生晶体质量问题包括缺陷形成的直接相互作用关系。随后的Part G展示了结晶材料特性和分析的发展。Part F和G说明了预测工具和分析技术在帮助高质量的大尺寸晶体生长工艺的设计和控制在方面是非常好用的。

最后的Part H致力于精选这一领域的部分现代课题，例如蛋白质晶体生长、凝胶结晶、原位结构、单晶闪烁材料的生长、光电材料和线切割大晶体薄膜。

我们希望这本施普林格手册对那些学习晶体生长的研究生，那些从事或即将从事这一领域研究的来自学术界和工业领域的研究人员、科学家和工程师以及那些制备晶体的人是有帮助的。

我们对施普林格的Dr. Claus Acheron, Dr. Werner Skolaut和le-tex的Ms Anne Strobach的特别努力表示真诚的感谢，没有他们本书将无法呈现。

我们感谢我们的作者编写了详尽的章节内容和在本书出版期间对我们的耐心。一位编者(GD)感谢他的家庭成员和Dr. Kedar Gupta(ARC Energy的CEO)，感谢他们在本书编写期间的大力支持和鼓励。还对Peter Rudolf, David Bliss, Ishwara Bhat和Partha Dutta在A、B、E部分的编写中所给予的帮助表示感谢。

Nashua, New Hampshire, April 2010
Mysore, India
Denton, Texas
Stony Brook, New York

G. Dhanaraj
K. Byrappa
V. Prasad
M. Dudley

Preface

Over the years, many successful attempts have been made to describe the art and science of crystal growth, and many review articles, monographs, symposium volumes, and handbooks have been published to present comprehensive reviews of the advances made in this field. These publications are testament to the growing interest in both bulk and thin-film crystals because of their electronic, optical, mechanical, microstructural, and other properties, and their diverse scientific and technological applications. Indeed, most modern advances in semiconductor and optical devices would not have been possible without the development of many elemental, binary, ternary, and other compound crystals of varying properties and large sizes. The literature devoted to basic understanding of growth mechanisms, defect formation, and growth processes as well as the design of growth systems is therefore vast.

The objective of this Springer Handbook is to present the state of the art of selected topical areas of both bulk and thin-film crystal growth. Our goal is to make readers understand the basics of the commonly employed growth processes, materials produced, and defects generated. To accomplish this, we have selected more than 50 leading scientists, researchers, and engineers, and their many collaborators from 22 different countries, to write chapters on the topics of their expertise. These authors have written 52 chapters on the fundamentals of crystal growth and defect formation; bulk growth from the melt, solution, and vapor; epitaxial growth; modeling of growth processes and defects; and techniques of defect characterization, as well as some contemporary special topics.

This Springer Handbook is divided into seven parts. Part A presents the fundamentals: an overview of the growth and characterization techniques, followed by the state of the art of nucleation at surfaces, morphology of crystals grown from solutions, nucleation of dislocation during growth, and defect formation and morphology.

Part B is devoted to bulk growth from the melt, a method critical to producing large-size crystals. The

chapters in this part describe the well-known processes such as Czochralski, Kyropoulos, Bridgman, and floating zone, and focus specifically on recent advances in improving these methodologies such as application of magnetic fields, orientation of the growth axis, introduction of a pedestal, and shaped growth. They also cover a wide range of materials from silicon and III–V compounds to oxides and fluorides.

The third part, Part C of the book, focuses on solution growth. The various aspects of hydrothermal growth are discussed in two chapters, while three other chapters present an overview of the nonlinear and laser crystals, KTP and KDP. The knowledge on the effect of gravity on solution growth is presented through a comparison of growth on Earth versus in a microgravity environment.

The topic of Part D is vapor growth. In addition to presenting an overview of vapor growth, this part also provides details on vapor growth of silicon carbide, gallium nitride, aluminum nitride, and organic semiconductors. This is followed by chapters on epitaxial growth and thin films in Part E. The topics range from chemical vapor deposition to liquid-phase epitaxy to pulsed laser and pulsed electron deposition.

Modeling of both growth processes and defect formation is presented in Part F. These chapters demonstrate the direct correlation between the process parameters and quality of the crystal produced, including the formation of defects. The subsequent Part G presents the techniques that have been developed for crystalline material characterization and analysis. The chapters in Parts F and G demonstrate how well predictive tools and analytical techniques have helped the design and control of growth processes for better-quality crystals of large sizes.

The final Part H is devoted to some selected contemporary topics in this field, such as protein crystal growth, crystallization from gels, in situ structural studies, growth of single-crystal scintillation materials, photovoltaic materials, and wire-saw slicing of large crystals to produce wafers.

We hope this Springer Handbook will be useful to graduate students studying crystal growth and to re-

searchers, scientists, and engineers from academia and industry who are conducting or intend to conduct research in this field as well as those who grow crystals.

We would like to express our sincere thanks to Dr. Claus Acheron and Dr. Werner Skolaut of Springer and Ms Anne Strohbach of *le-tex* for their extraordinary efforts without which this handbook would not have taken its final shape.

We thank our authors for writing comprehensive chapters and having patience with us during the publication of this Handbook. One of the editors (GD) would

like to thank his family members and Dr. Kedar Gupta (CEO of ARC Energy) for their generous support and encouragement during the entire course of editing this handbook. Acknowledgements are also due to Peter Rudolf, David Bliss, Ishwara Bhat, and Partha Dutta for their help in editing Parts A, B, E, and H, respectively.

Nashua, New Hampshire, April 2010
Mysore, India
Denton, Texas
Stony Brook, New York

G. Dhanaraj
K. Byrappa
V. Prasad
M. Dudley

About the Editors

Govindhan Dhanaraj is the Manager of Crystal Growth Technologies at Advanced Renewable Energy Company (ARC Energy) at Nashua, New Hampshire (USA) focusing on the growth of large size sapphire crystals for LED lighting applications, characterization and related crystal growth furnace development. He received his PhD from the Indian Institute of Science, Bangalore and his Master of Science from Anna University (India). Immediately after his doctoral degree, Dr. Dhanaraj joined a National Laboratory, presently known as Rajaramanna Center for Advanced Technology in India, where he established an advanced Crystal Growth Laboratory for the growth of optical and laser crystals. Prior to joining ARC Energy, Dr. Dhanaraj served as a Research Professor at the Department of Materials Science and Engineering, Stony Brook University, NY, and also held a position of Research Assistant Professor at Hampton University, VA. During his 25 years of focused expertise in crystal growth research, he has developed optical, laser and semiconductor bulk crystals and SiC epitaxial films using solution, flux, Czochralski, Bridgeman, gel and vapor methods, and characterized them using x-ray topography, synchrotron topography, chemical etching and optical and atomic force microscopic techniques. He co-organized a symposium on Industrial Crystal Growth under the 17th American Conference on Crystal Growth and Epitaxy in conjunction with the 14th US Biennial Workshop on Organometallic Vapor Phase Epitaxy held at Lake Geneva, WI in 2009. Dr. Dhanaraj has delivered invited lectures and also served as session chairman in many crystal growth and materials science meetings. He has published over 100 papers and his research articles have attracted over 250 rich citations.



Kullaiah Byrappa received his Doctor's degree in Crystal Growth from the Moscow State University, Moscow in 1981. He is Professor of Materials Science, Head of the Crystal Growth Laboratory, and Director of the Internal Quality Assurance Cell of the University of Mysore, India. His current research is in crystal engineering of polyscale materials through novel solution processing routes, particularly covering hydrothermal, solvothermal and supercritical methods. Professor Byrappa has co-authored the Handbook of Hydrothermal Technology, and edited 4 books as well as two special editions of Journal of Materials Science, and published 180 research papers including 26 invited reviews and book chapters on various aspects of novel routes of solution processing. Professor Byrappa has delivered over 60 keynote and invited lectures at International Conferences, and several hundreds of colloquia and seminars at various institutions around the world. He has also served as chair and co-chair for numerous international conferences. He is a Fellow of the World Academy of Ceramics. Professor Byrappa is serving in several international committees and commissions related to crystallography, crystal growth, and materials science. He is the Founder Secretary of the International Solvothermal and Hydrothermal Association. Professor Byrappa is a recipient of several awards such as the Sir C.V. Raman Award, Materials Research Society of India Medal, and the Golden Jubilee Award of the University of Mysore.



Vishwanath "Vish" Prasad is the Vice President for Research and Economic Development and Professor of Mechanical and Energy Engineering at the University of North Texas (UNT), one of the largest university in the state of Texas. He received his PhD from the University of Delaware (USA), his Masters of Technology from the Indian Institute of Technology, Kanpur, and his bachelor's from Patna University in India all in Mechanical Engineering. Prior to joining UNT in 2007, Dr. Prasad served as the Dean at Florida International University (FIU) in Miami, where he also held the position of Distinguished Professor of Engineering. Previously, he has served as a Leading Professor of Mechanical Engineering at Stony Brook University, New York, as an Associate Professor and Assistant Professor at Columbia University. He has received many special recognitions for his contributions to engineering education. Dr. Prasad's research interests include thermo-fluid sciences, energy systems, electronic materials, and computational materials processing. He has published over 200 articles, edited/co-edited several books and organized numerous conferences, symposia, and workshops. He serves as the lead editor of the Annual Review of Heat Transfer. In the past, he has served as an Associate Editor of the ASME Journal of Heat. Dr. Prasad is an elected Fellow of the American Society of Mechanical Engineers (ASME), and has served as a member of the USRA Microgravity Research Council. Dr. Prasad's research has focused on bulk growth of silicon, III-V compounds, and silicon carbide; growth of large diameter Si tube; design of crystal growth systems; and sputtering and chemical vapor deposition of thin films. He is also credited to initiate research on wire saw cutting of large crystals to produce wafers with much reduced material loss. Dr. Prasad's research has been well funded by US National Science Foundation (NSF), US Department of Defense, US Department of Energy, and industry.



Michael Dudley received his Doctoral Degree in Engineering from Warwick University, UK, in 1982. He is Professor and Chair of the Materials Science and Engineering Department at Stony Brook University, New York, USA. He is director of the Stony Brook Synchrotron Topography Facility at the National Synchrotron Light Source at Brookhaven National Laboratory, Upton New York. His current research focuses on crystal growth and characterization of defect structures in single crystals with a view to determining their origins. The primary technique used is synchrotron topography which enables analysis of defects and generalized strain fields in single crystals in general, with particular emphasis on semiconductor, optoelectronic, and optical crystals. Establishing the relationship between crystal growth conditions and resulting defect distributions is a particular thrust area of interest to Dudley, as is the correlation between electronic/optoelectronic device performance and defect distribution. Other techniques routinely used in such analysis include transmission electron microscopy, high resolution triple-axis x-ray diffraction, atomic force microscopy, scanning electron microscopy, Nomarski optical microscopy, conventional optical microscopy, IR microscopy and fluorescent laser scanning confocal microscopy. Dudley's group has played a prominent role in the development of SiC and AlN growth, characterizing crystals grown by many of the academic and commercial entities involved enabling optimization of crystal quality. He has co-authored some 315 refereed articles and 12 book chapters, and has edited 5 books. He is currently a member of the Editorial Board of Journal of Applied Physics and Applied Physics Letters and has served as Chair or Co-Chair for numerous international conferences.



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